

ABSTRACT OF THE DISCLOSURE

[00137] A method of measuring phase of a pseudorandom (PN) sequence of chips, the method includes: generating a reference model exhibiting a reference phase, the reference phase adjustable to facilitate alignment with the phase of the pseudorandom sequence; establishing a plurality of pulsed-windows over which a plurality of samples of the pseudorandom sequence are collected for a selected accumulation interval; and accumulating the plurality of samples for each pulsed-window of the plurality of pulsed windows to form a plurality of accumulated sums. The method also includes: compensating each accumulated sum to form at least one compensated sum, if a number of level transitions and non-transitions of the pseudorandom sequence is not equal; and combining the compensated sum to determine a phase error from the plurality of compensated sums, the phase error corresponding to a phase difference between the reference phase and the phase of the pseudorandom sequence.